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Notice of Allowability	Application No.	Applicant(s)
	10/620,702	CHENG ET AL.
	Examiner	Art Unit
	Paresh Patel	2829
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.		
1. This communication is responsive to 02/22/05 and 04/04/2005.		
2. The allowed claim(s) is/are <u>1-12</u> .		
3. The drawings filed on 28 October 2003 are accepted by the Examiner.		
<ul> <li>4.  Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).</li> <li>a)  All b)  Some* c) None of the:</li> <li>1.  Certified copies of the priority documents have been received.</li> <li>2.  Certified copies of the priority documents have been received in Application No</li> <li>3.  Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> </ul>		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		
5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.		
<ul> <li>6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.</li> <li>(a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached</li> <li>1) hereto or 2) to Paper No./Mail Date</li> <li>(b) including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).</li> </ul>		
7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.		
<ul> <li>Attachment(s)</li> <li>1. ☑ Notice of References Cited (PTO-892)</li> <li>2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>3. ☐ Paper No./Mail Date 77</li></ul>	6. ☐ Interview Summary Paper No./Mail Date 8), 7. ☐ Examiner's Amendm	e

## Allowable Subject Matter

- 1. Claims 1-12 are allowed.
- 2. The following is an examiner's statement of reasons for allowance:

After reviewing the prior art references, the Examiner found that Applicants' argument in Remarks pages 3-5, filed on 02/22/2005 are persuasive for placing the claims 1-12 in condition for allowance.

Furthermore, no prior art has been found to meet the limitations of claims 1-10 calling for a method of inspecting a board with a circuit pattern including at least a porous low-permittivity material comprising the step of reducing damage, including shrinkage to the circuit pattern due to primary electron beam by controlling the irradiation energy and density of the primary electron beam, as further defined at claims 1, 8 and 10.

No prior art has been found to meet the limitations of claims 11-12 calling for an apparatus for inspecting a board with a circuit pattern including at least a porous low-permittivity hydrogensilsesquioxane material comprising means for inspecting circuit pattern damage including shrinkage to the circuit pattern by the primary electron beam being reduced by controlling the irradiation energy and density of the primary electron beam as further defined at claim 11.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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## Conclusion

3. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paresh Patel whose telephone number is 571-272-1968. The examiner can normally be reached on 8:00 to 4:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nestor Ramirez can be reached on 571-272-2034. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Paresh Patel Primary Examiner Art Unit 2829 Page 3

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